



FIG. 8.4 Auger electron spectroscopy (AES) depth profile for three contacts to YBCO: (a) indium-solder contact; (b) Ag/YBCO contact [given an oxygen anneal at a very low temperature (250 °C)]; and (c) Ag/YBCO contact fully oxygen annealed at 600 °C for 1 h. Relative amounts of each element are indicated by the Auger electron intensity, plotted along the vertical axis in arbitrary units; position across the interface is indicated by the ion sputter time plotted along the horizontal axis. (From Ekin et al. 1988a.)